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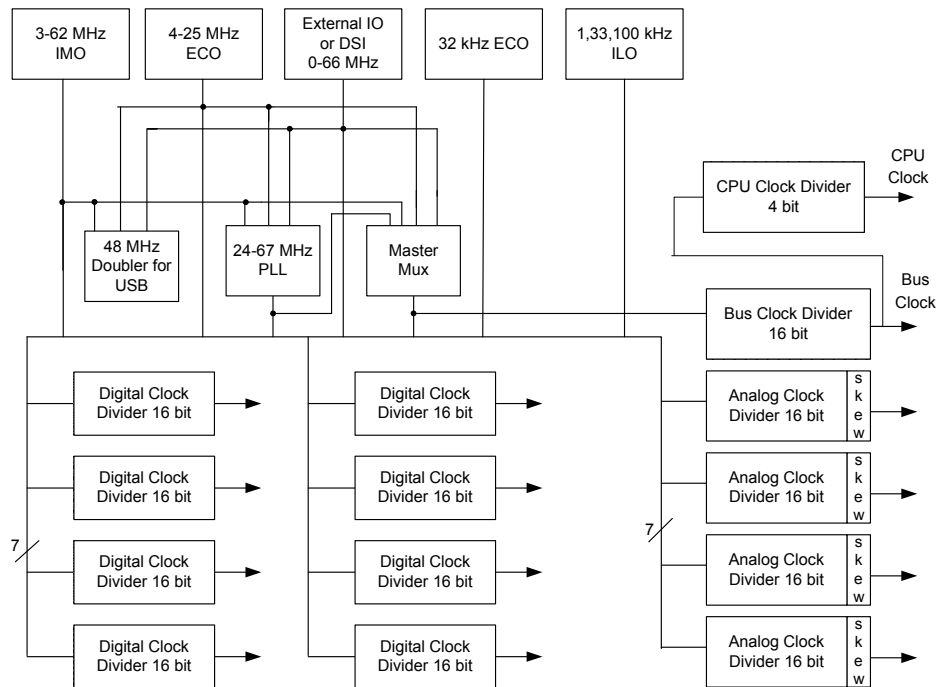
"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	8051
Core Size	8-Bit
Speed	67MHz
Connectivity	CANbus, EBI/EMI, I ² C, LINbus, SPI, UART/USART
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	62
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x20b; D/A 4x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3866axa-035

Figure 6-1. Clocking Subsystem



6.1.1 Internal Oscillators

6.1.1.1 Internal Main Oscillator

In most designs the IMO is the only clock source required, due to its ± 1 -percent accuracy. The IMO operates with no external components and outputs a stable clock. A factory trim for each frequency range is stored in the device. With the factory trim, tolerance varies from ± 1 percent at 3 MHz, up to ± 7 percent at 62 MHz. The IMO, in conjunction with the PLL, allows generation of other clocks up to the device's maximum frequency (see PLL). The IMO provides clock outputs at 3, 6, 12, 24, 48, and 62 MHz.

6.1.1.2 Clock Doubler

The clock doubler outputs a clock at twice the frequency of the input clock. The doubler works at input frequency of 24 MHz, providing 48 MHz for the USB. It can be configured to use a clock from the IMO, MHzECO, or the DSI (external pin).

6.1.1.3 PLL

The PLL allows low-frequency, high-accuracy clocks to be multiplied to higher frequencies. This is a trade off between higher clock frequency and accuracy and, higher power consumption and increased startup time.

The PLL block provides a mechanism for generating clock frequencies based upon a variety of input sources. The PLL outputs clock frequencies in the range of 24 to 67 MHz. Its input and feedback dividers supply 4032 discrete ratios to create almost any desired clock frequency. The accuracy of the PLL output depends on the accuracy of the PLL input source. The most common PLL use is to multiply the IMO clock at 3 MHz, where it is most accurate, to generate the other clocks up to the device's maximum frequency.

The PLL achieves phase lock within 250 μ s (verified by bit setting). It can be configured to use a clock from the IMO, MHzECO or DSI (external pin). The PLL clock source can be

used until lock is complete and signaled with a lock bit. The lock signal can be routed through the DSI to generate an interrupt. Disable the PLL before entering low-power modes.

6.1.1.4 Internal Low-Speed Oscillator

The ILO provides clock frequencies for low-power consumption, including the watchdog timer, and sleep timer. The ILO generates up to three different clocks: 1 kHz, 33 kHz, and 100 kHz. The 1-kHz clock (CLK1K) is typically used for a background 'heartbeat' timer. This clock inherently lends itself to low-power supervisory operations such as the watchdog timer and long sleep intervals using the central timewheel (CTW).

The central timewheel is a 1-kHz, free running, 13-bit counter clocked by the ILO. The central timewheel is always enabled, except in hibernate mode and when the CPU is stopped during debug on chip mode. It can be used to generate periodic interrupts for timing purposes or to wake the system from a low-power mode. Firmware can reset the central timewheel. Systems that require accurate timing should use the RTC capability instead of the central timewheel.

The 100-kHz clock (CLK100K) can be used as a low power master clock. It can also generate time intervals using the fast timewheel.

The fast timewheel is a 5-bit counter, clocked by the 100-kHz clock. It features programmable settings and automatically resets when the terminal count is reached. An optional interrupt can be generated each time the terminal count is reached. This enables flexible, periodic interrupts of the CPU at a higher rate than is allowed using the central timewheel.

The 33-kHz clock (CLK33K) comes from a divide-by-3 operation on CLK100K. This output can be used as a reduced accuracy version of the 32.768-kHz ECO clock with no need for a crystal.

6.4.1 Drive Modes

Each GPIO and SIO pin is individually configurable into one of the eight drive modes listed in Table 6-5. Three configuration bits are used for each pin (DM[2:0]) and set in the PRTxDM[2:0] registers. Figure 6-10 depicts a simplified pin view based on each of the eight drive modes. Table 6-5 shows the I/O pin's drive state based on the port data register value or digital array signal if bypass mode is selected. Note that the actual I/O pin voltage is determined by a combination of the selected drive mode and the load at the pin. For example, if a GPIO pin is configured for resistive pull-up mode and driven high while the pin is floating, the voltage measured at the pin is a high logic state. If the same GPIO pin is externally tied to ground then the voltage unmeasured at the pin is a low logic state.

Figure 6-10. Drive Mode

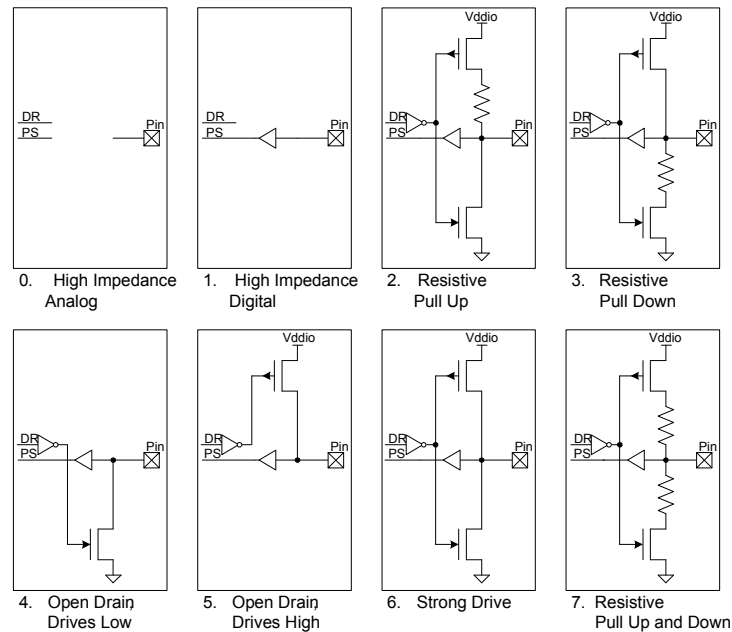


Table 6-5. Drive Modes

Diagram	Drive Mode	PRTxDM2	PRTxDM1	PRTxDM0	PRTxDR = 1	PRTxDR = 0
0	High impedance analog	0	0	0	High Z	High Z
1	High Impedance digital	0	0	1	High Z	High Z
2	Resistive pull-up ^[14]	0	1	0	Res High (5K)	Strong Low
3	Resistive pull-down ^[14]	0	1	1	Strong High	Res Low (5K)
4	Open drain, drives low	1	0	0	High Z	Strong Low
5	Open drain, drive high	1	0	1	Strong High	High Z
6	Strong drive	1	1	0	Strong High	Strong Low
7	Resistive pull-up and pull-down ^[14]	1	1	1	Res High (5K)	Res Low (5K)

Note

¹⁴. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

6.4.5 Pin Interrupts

All GPIO and SIO pins are able to generate interrupts to the system. All eight pins in each port interface to their own Port Interrupt Control Unit (PICU) and associated interrupt vector. Each pin of the port is independently configurable to detect rising edge, falling edge, both edge interrupts, or to not generate an interrupt.

Depending on the configured mode for each pin, each time an interrupt event occurs on a pin, its corresponding status bit of the interrupt status register is set to '1' and an interrupt request is sent to the interrupt controller. Each PICU has its own interrupt vector in the interrupt controller and the pin status register providing easy determination of the interrupt source down to the pin level.

Port pin interrupts remain active in all sleep modes allowing the PSoC device to wake from an externally generated interrupt. While level sensitive interrupts are not directly supported; UDB provide this functionality to the system when needed.

6.4.6 Input Buffer Mode

GPIO and SIO input buffers can be configured at the port level for the default CMOS input thresholds or the optional LVTTTL input thresholds. All input buffers incorporate Schmitt triggers for input hysteresis. Additionally, individual pin input buffers can be disabled in any drive mode.

6.4.7 I/O Power Supplies

Up to four I/O pin power supplies are provided depending on the device and package. Each I/O supply must be less than or equal to the voltage on the chip's analog (VDDA) pin. This feature allows users to provide different I/O voltage levels for different pins on the device. Refer to the specific device package pinout to determine VDDIO capability for a given port and pin. The SIO port pins support an additional regulated high output capability, as described in [Adjustable Output Level](#).

6.4.8 Analog Connections

These connections apply only to GPIO pins. All GPIO pins may be used as analog inputs or outputs. The analog voltage present on the pin must not exceed the VDDIO supply voltage to which the GPIO belongs. Each GPIO may connect to one of the analog global busses or to one of the analog mux buses to connect any pin to any internal analog resource such as ADC or comparators. In addition, select pins provide direct connections to specific analog features such as the high current DACs or uncommitted opamps.

6.4.9 CapSense

This section applies only to GPIO pins. All GPIO pins may be used to create CapSense buttons and sliders^[15]. See the ["CapSense"](#) section on page 58 for more information.

6.4.10 LCD Segment Drive

This section applies only to GPIO pins. All GPIO pins may be used to generate Segment and Common drive signals for direct glass drive of LCD glass. See the ["LCD Direct Drive"](#) section on page 57 for details.

6.4.11 Adjustable Output Level

This section applies only to SIO pins. SIO port pins support the ability to provide a regulated high output level for interface to external signals that are lower in voltage than the SIO's respective VDDIO. SIO pins are individually configurable to output either the standard VDDIO level or the regulated output, which is based on an internally generated reference. Typically a voltage DAC (VDAC) is used to generate the reference (see [Figure 6-11](#)). The ["DAC"](#) section on page 59 has more details on VDAC use and reference routing to the SIO pins. Resistive pullup and pull-down drive modes are not available with SIO in regulated output mode.

6.4.12 Adjustable Input Level

This section applies only to SIO pins. SIO pins by default support the standard CMOS and LVTTTL input levels but also support a differential mode with programmable levels. SIO pins are grouped into pairs. Each pair shares a reference generator block which is used to set the digital input buffer reference level for interface to external signals that differ in voltage from VDDIO. The reference sets the pins voltage threshold for a high logic level (see [Figure 6-11](#)). Available input thresholds are:

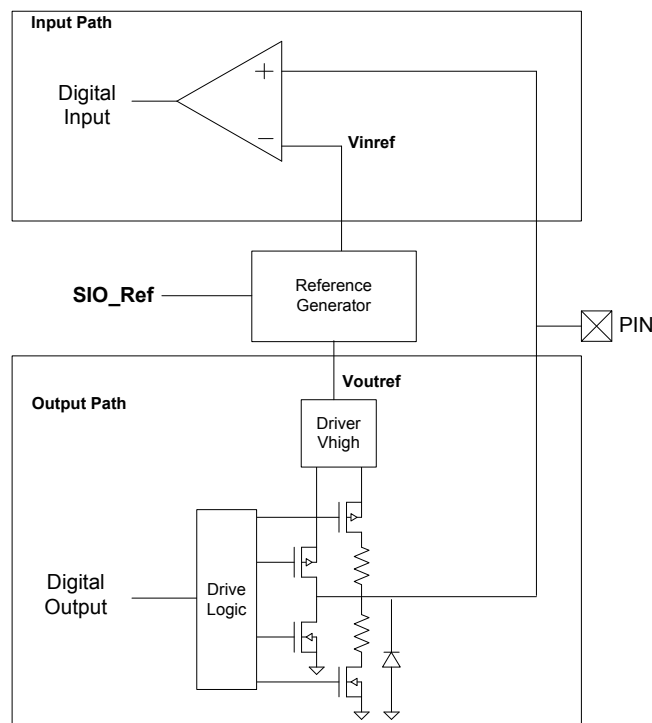
- $0.5 \times \text{VDDIO}$
- $0.4 \times \text{VDDIO}$
- $0.5 \times V_{\text{REF}}$
- V_{REF}

Typically a voltage DAC (VDAC) generates the V_{REF} reference. ["DAC"](#) section on page 59 has more details on VDAC use and reference routing to the SIO pins.

Note

15. GPIOs with opamp outputs are not recommended for use with CapSense.

Figure 6-11. SIO Reference for Input and Output



6.4.13 SIO as Comparator

This section applies only to SIO pins. The adjustable input level feature of the SIOs as explained in the [Adjustable Input Level](#) section can be used to construct a comparator. The threshold for the comparator is provided by the SIO's reference generator. The reference generator has the option to set the analog signal routed through the analog global line as threshold for the comparator. Note that a pair of SIO pins share the same threshold. The digital input path in [Figure 6-8](#) on page 35 illustrates this functionality. In the figure, 'Reference level' is the analog signal routed through the analog global. The hysteresis feature can also be enabled for the input buffer of the SIO, which increases noise immunity for the comparator.

6.4.14 Hot Swap

This section applies only to SIO pins. SIO pins support 'hot swap' capability to plug into an application without loading the signals that are connected to the SIO pins even when no power is applied to the PSoC device. This allows the unpowered PSoC to maintain a high impedance load to the external device while also preventing the PSoC from being powered through a SIO pin's protection diode.

Powering the device up or down while connected to an operational I2C bus may cause transient states on the SIO pins. The overall I2C bus design should take this into account.

6.4.15 Over Voltage Tolerance

All I/O pins provide an over voltage tolerance feature at any operating V_{DD} .

- There are no current limitations for the SIO pins as they present a high impedance load to the external circuit where $V_{DDIO} \leq V_{IN} \leq 5.5$ V.
- The GPIO pins must be limited to 100 μ A using a current limiting resistor. GPIO pins clamp the pin voltage to approximately one diode above the VDDIO supply where $V_{DDIO} \leq V_{IN} \leq V_{DDA}$.
- In case of a GPIO pin configured for analog input/output, the analog voltage on the pin must not exceed the VDDIO supply voltage to which the GPIO belongs.

A common application for this feature is connection to a bus such as I²C where different devices are running from different supply voltages. In the I²C case, the PSoC chip is configured into the Open Drain, Drives Low mode for the SIO pin. This allows an external pull-up to pull the I²C bus voltage above the PSoC pin supply. For example, the PSoC chip could operate at 1.8 V, and an external device could run from 5 V. Note that the SIO pin's V_{IH} and V_{IL} levels are determined by the associated VDDIO supply pin. The SIO pin must be in one of the following modes: 0 (high impedance analog), 1 (high impedance digital), or 4 (open drain drives low). See [Figure 6-10](#) for details. Absolute maximum ratings for the device must be observed for all I/O pins.

6.4.16 Reset Configuration

While reset is active all I/Os are reset to and held in the High Impedance Analog state. After reset is released, the state can be reprogrammed on a port-by-port basis to pull-down or pull-up. To ensure correct reset operation, the port reset configuration data is stored in special nonvolatile registers. The stored reset data is automatically transferred to the port reset configuration registers at reset release.

6.4.17 Low-Power Functionality

In all low-power modes the I/O pins retain their state until the part is awakened and changed or reset. To awaken the part, use a pin interrupt, because the port interrupt logic continues to function in all low-power modes.

6.4.18 Special Pin Functionality

Some pins on the device include additional special functionality in addition to their GPIO or SIO functionality. The specific special function pins are listed in [Pinouts](#) on page 5. The special features are:

- Digital
 - 4- to 25-MHz crystal oscillator
 - 32.768-kHz crystal oscillator
 - Wake from sleep on I²C address match. Any pin can be used for I²C if wake from sleep is not required.
 - JTAG interface pins
 - SWD interface pins
 - SWV interface pins
 - External reset
- Analog
 - Opamp inputs and outputs
 - High current IDAC outputs
 - External reference inputs

6.4.19 JTAG Boundary Scan

The device supports standard JTAG boundary scan chains on all I/O pins for board level test.

7. Digital Subsystem

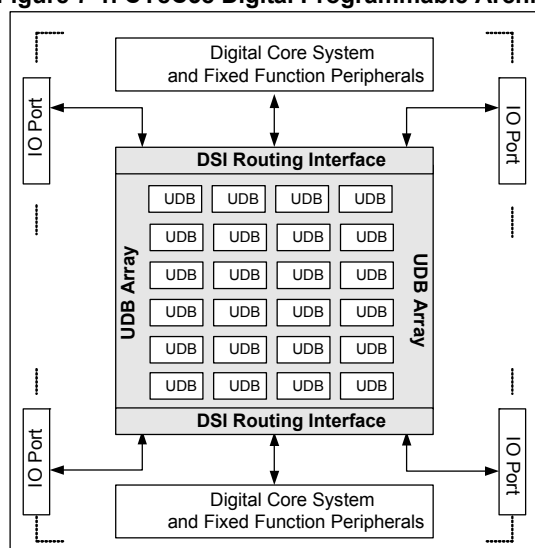
The digital programmable system creates application specific combinations of both standard and advanced digital peripherals and custom logic functions. These peripherals and logic are then interconnected to each other and to any pin on the device, providing a high level of design flexibility and IP security.

The features of the digital programmable system are outlined here to provide an overview of capabilities and architecture. You do not need to interact directly with the programmable digital system at the hardware and register level. PSoC Creator provides a high level schematic capture graphical interface to automatically place and route resources similar to PLDs.

The main components of the digital programmable system are:

- **UDB** – These form the core functionality of the digital programmable system. UDBs are a collection of uncommitted logic (PLD) and structural logic (Datapath) optimized to create all common embedded peripherals and customized functionality that are application or design specific.
- **Universal digital block array** – UDB blocks are arrayed within a matrix of programmable interconnect. The UDB array structure is homogeneous and allows for flexible mapping of digital functions onto the array. The array supports extensive and flexible routing interconnects between UDBs and the Digital System Interconnect.
- **Digital system interconnect (DSI)** – Digital signals from UDBs, fixed function peripherals, I/O pins, interrupts, DMA, and other system core signals are attached to the digital system interconnect to implement full featured device connectivity. The DSI allows any digital function to any pin or other feature routability when used with the universal digital block array.

Figure 7-1. CY8C38 Digital Programmable Architecture



7.1 Example Peripherals

The flexibility of the CY8C38 family's UDBs and analog blocks allow the user to create a wide range of components (peripherals). The most common peripherals were built and characterized by Cypress and are shown in the PSoC Creator component catalog, however, users may also create their own custom components using PSoC Creator. Using PSoC Creator, users may also create their own components for reuse within their organization, for example sensor interfaces, proprietary algorithms, and display interfaces.

The number of components available through PSoC Creator is too numerous to list in the data sheet, and the list is always growing. An example of a component available for use in CY8C38 family, but, not explicitly called out in this data sheet is the UART component.

7.1.1 Example Digital Components

The following is a sample of the digital components available in PSoC Creator for the CY8C38 family. The exact amount of hardware resources (UDBs, routing, RAM, flash) used by a component varies with the features selected in PSoC Creator for the component.

- **Communications**
 - I²C
 - UART
 - SPI
- **Functions**
 - EMIF
 - PWMs
 - Timers
 - Counters
- **Logic**
 - NOT
 - OR
 - XOR
 - AND

7.1.2 Example Analog Components

The following is a sample of the analog components available in PSoC Creator for the CY8C38 family. The exact amount of hardware resources (SC/CT blocks, routing, RAM, flash) used by a component varies with the features selected in PSoC Creator for the component.

- **Amplifiers**
 - TIA
 - PGA
 - opamp
- **ADC**
 - Delta-sigma
- **DACs**
 - Current
 - Voltage
 - PWM
- **Comparators**
- **Mixers**

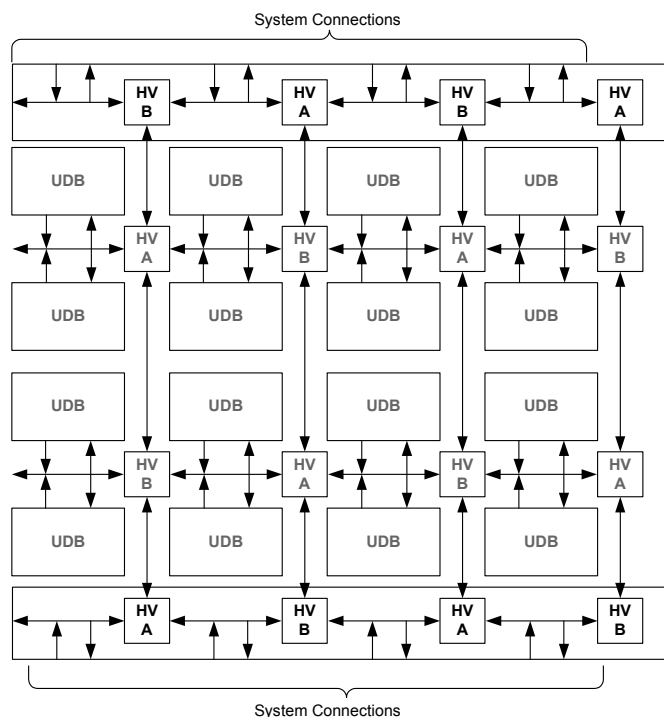
7.2.3.2 Clock Generation

Each subcomponent block of a UDB including the two PLDs, the datapath, and Status and Control, has a clock selection and control block. This promotes a fine granularity with respect to allocating clocking resources to UDB component blocks and allows unused UDB resources to be used by other functions for maximum system efficiency.

7.3 UDB Array Description

Figure 7-7 shows an example of a 16 UDB array. In addition to the array core, there are DSI routing interfaces at the top and bottom of the array. Other interfaces that are not explicitly shown include the system interfaces for bus and clock distribution. The UDB array includes multiple horizontal and vertical routing channels each comprised of 96 wires. The wire connections to UDBs, at horizontal/vertical intersection and at the DSI interface are highly permutable providing efficient automatic routing in PSoC Creator. Additionally the routing allows wire by wire segmentation along the vertical and horizontal routing to further increase routing flexibility and capability.

Figure 7-7. Digital System Interface Structure

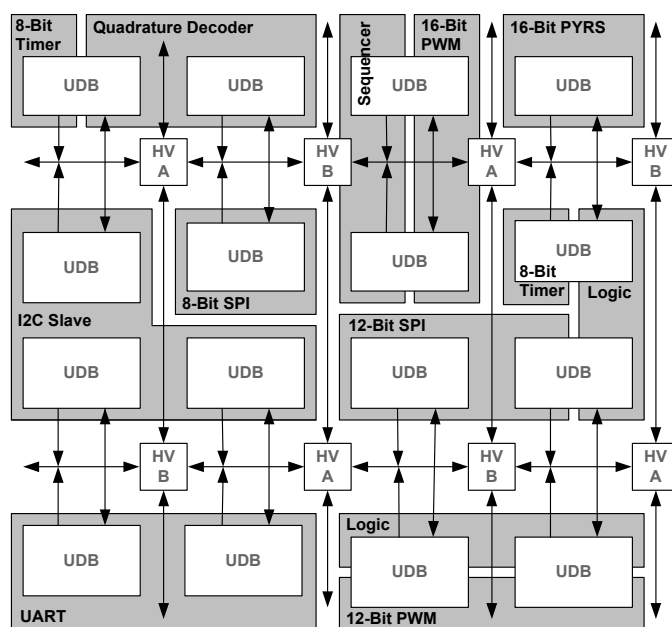


7.3.1 UDB Array Programmable Resources

Figure 7-8 shows an example of how functions are mapped into a bank of 16 UDBs. The primary programmable resources of the UDB are two PLDs, one datapath and one status/control register. These resources are allocated independently, because they have independently selectable clocks, and therefore unused blocks are allocated to other unrelated functions.

An example of this is the 8-bit timer in the upper left corner of the array. This function only requires one datapath in the UDB, and therefore the PLD resources may be allocated to another function. A function such as a Quadrature Decoder may require more PLD logic than one UDB can supply and in this case can utilize the unused PLD blocks in the 8-bit Timer UDB. Programmable resources in the UDB array are generally homogeneous so functions can be mapped to arbitrary boundaries in the array.

Figure 7-8. Function Mapping Example in a Bank of UDBs



7.4 DSI Routing Interface Description

The DSI routing interface is a continuation of the horizontal and vertical routing channels at the top and bottom of the UDB array core. It provides general purpose programmable routing between device peripherals, including UDBs, I/Os, analog peripherals, interrupts, DMA and fixed function peripherals.

Figure 7-9 illustrates the concept of the digital system interconnect, which connects the UDB array routing matrix with other device peripherals. Any digital core or fixed function peripheral that needs programmable routing is connected to this interface.

Signals in this category include:

- Interrupt requests from all digital peripherals in the system.
- DMA requests from all digital peripherals in the system.
- Digital peripheral data signals that need flexible routing to I/Os.
- Digital peripheral data signals that need connections to UDBs.
- Connections to the interrupt and DMA controllers.
- Connection to I/O pins.
- Connection to analog system digital signals.

7.9 Digital Filter Block

Some devices in the CY8C38 family of devices have a dedicated HW accelerator block used for digital filtering. The DFB has a dedicated multiplier and accumulator that calculates a 24-bit by 24-bit multiply accumulate in one bus clock cycle. This enables the mapping of a direct form FIR filter that approaches a computation rate of one FIR tap for each clock cycle. The MCU can implement any of the functions performed by this block, but at a slower rate that consumes MCU bandwidth.

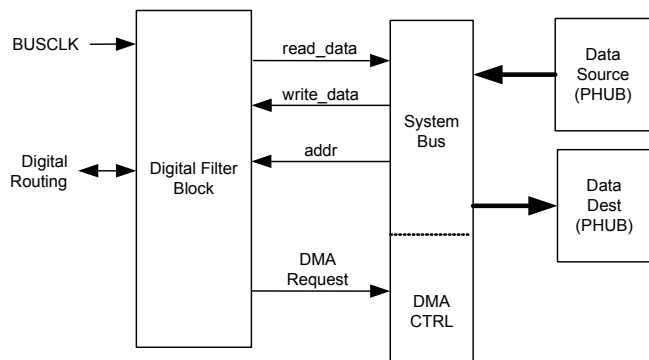
The heart of the DFB is a datapath (DP), which is the numerical calculation unit of the DFB. The DP is a 24-bit fixed-point numerical processor containing a 48-bit multiply and accumulate function (MAC), a multi-function ALU, sample and coefficient data RAMs as well as data routing, shifting, holding and rounding functions.

In the MAC, two 24-bit values can be multiplied and the result added to the 48-bit accumulator in each bus clock cycle. The MAC is the only portion of the DP that is wider than 24 bits. All results from the MAC are passed on to the ALU as 24-bit values representing the high-order 24 bits in the accumulator shifted by one (bits 46:23). The MAC assumes an implied binary point after the most significant bit.

The DP also contains an optimized ALU that supports add, subtract, comparison, threshold, absolute value, squelch, saturation, and other functions. The DP unit is controlled by seven control fields totaling 18 bits coming from the DFB Controller. For more information see the TRM.

The PSoC Creator interface provides a wizard to implement FIR and IIR digital filters with coefficients for LPF, BPF, HPF, Notch and arbitrary shape filters. 64 pairs of data and coefficients are stored. This enables a 64 tap FIR filter or up to 4 16 tap filters of either FIR or IIR formulation.

Figure 7-19. DFB Application Diagram (pwr/gnd not shown)



The typical use model is for data to be supplied to the DFB over the system bus from another on-chip system data source such as an ADC. The data typically passes through main memory or is directly transferred from another chip resource through DMA. The DFB processes this data and passes the result to another on-chip resource such as a DAC or main memory through DMA on the system bus.

Data movement in or out of the DFB is typically controlled by the system DMA controller but can be moved directly by the MCU.

8. Analog Subsystem

The analog programmable system creates application specific combinations of both standard and advanced analog signal processing blocks. These blocks are then interconnected to each other and also to any pin on the device, providing a high level of design flexibility and IP security. The features of the analog subsystem are outlined here to provide an overview of capabilities and architecture.

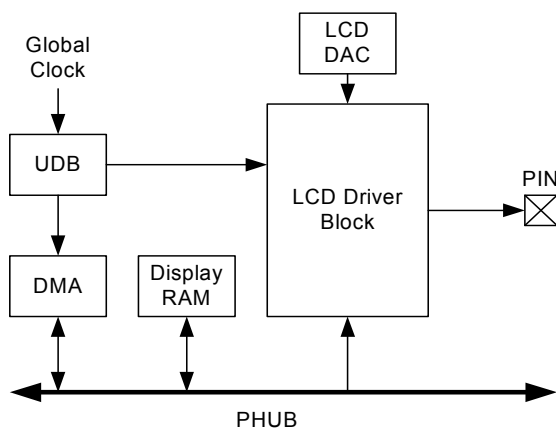
- Flexible, configurable analog routing architecture provided by analog globals, analog mux bus, and analog local buses.
- High resolution delta-sigma ADC.
- Up to four 8-bit DACs that provide either voltage or current output.
- Four comparators with optional connection to configurable LUT outputs.
- Up to four configurable switched capacitor/continuous time (SC/CT) blocks for functions that include opamp, unity gain buffer, programmable gain amplifier, transimpedance amplifier, and mixer.
- Up to four opamps for internal use and connection to GPIO that can be used as high current output buffers.
- CapSense subsystem to enable capacitive touch sensing.
- Precision reference for generating an accurate analog voltage for internal analog blocks.

PSoC Creator provides an LCD segment drive component. The component wizard provides easy and flexible configuration of LCD resources. You can specify pins for segments and commons along with other options. The software configures the device to meet the required specifications. This is possible because of the programmability inherent to PSoC devices.

Key features of the PSoC LCD segment system are:

- LCD panel direct driving
- Type A (standard) and Type B (low-power) waveform support
- Wide operating voltage range support (2 V to 5 V) for LCD panels
- Static, 1/2, 1/3, 1/4, 1/5 bias voltage levels
- Internal bias voltage generation through internal resistor ladder
- Up to 62 total common and segment outputs
- Up to 1/16 multiplex for a maximum of 16 backplane/common outputs
- Up to 62 front plane/segment outputs for direct drive
- Drives up to 736 total segments (16 backplane × 46 front plane)
- Up to 64 levels of software controlled contrast
- Ability to move display data from memory buffer to LCD driver through DMA (without CPU intervention)
- Adjustable LCD refresh rate from 10 Hz to 150 Hz
- Ability to invert LCD display for negative image
- Three LCD driver drive modes, allowing power optimization

Figure 8-10. LCD System



8.6.1 LCD Segment Pin Driver

Each GPIO pin contains an LCD driver circuit. The LCD driver buffers the appropriate output of the LCD DAC to directly drive the glass of the LCD. A register setting determines whether the pin is a common or segment. The pin's LCD driver then selects one of the six bias voltages to drive the I/O pin, as appropriate for the display data.

8.6.2 Display Data Flow

The LCD segment driver system reads display data and generates the proper output voltages to the LCD glass to produce the desired image. Display data resides in a memory buffer in the system SRAM. Each time you need to change the common and segment driver voltages, the next set of pixel data moves from the memory buffer into the Port Data Registers through the DMA.

8.6.3 UDB and LCD Segment Control

A UDB is configured to generate the global LCD control signals and clocking. This set of signals is routed to each LCD pin driver through a set of dedicated LCD global routing channels. In addition to generating the global LCD control signals, the UDB also produces a DMA request to initiate the transfer of the next frame of LCD data.

8.6.4 LCD DAC

The LCD DAC generates the contrast control and bias voltage for the LCD system. The LCD DAC produces up to five LCD drive voltages plus ground, based on the selected bias ratio. The bias voltages are driven out to GPIO pins on a dedicated LCD bias bus, as required.

8.7 CapSense

The CapSense system provides a versatile and efficient means for measuring capacitance in applications such as touch sense buttons, sliders, proximity detection, etc. The CapSense system uses a configuration of system resources, including a few hardware functions primarily targeted for CapSense. Specific resource usage is detailed in the CapSense component in PSoC Creator.

A capacitive sensing method using a Delta-sigma Modulator (CSD) is used. It provides capacitance sensing using a switched capacitor technique with a delta-sigma modulator to convert the sensing current to a digital code.

8.8 Temp Sensor

Die temperature is used to establish programming parameters for writing flash. Die temperature is measured using a dedicated sensor based on a forward biased transistor. The temperature sensor has its own auxiliary ADC.

Table 11-2. DC Specifications *(continued)*

Parameter	Description	Conditions		Min	Typ	Max	Units
	Sleep Mode ^[26]						
	CPU OFF RTC = ON (= ECO32K ON, in low power mode) Sleep timer = ON (= ILO ON at 1 kHz) ^[27] WDT = OFF I ² C Wake = OFF Comparator = OFF POR = ON SIO Pins in single ended input, unregulated output mode	V _{DD} = V _{DDIO} = 4.5 V–5.5 V	T = –40 °C	–	1.1	2.3	μA
			T = 25 °C	–	1.1	2.2	μA
			T = 85 °C	–	15	30	μA
			T = 125 °C	–	20.3	30	μA
		V _{DD} = V _{DDIO} = 2.7 V–3.6 V	T = –40 °C	–	1	2.2	μA
			T = 25 °C	–	1	2.1	μA
			T = 85 °C	–	12	28	μA
			T = 125 °C	–	18.5	28	μA
		V _{CC} = V _{DDIO} = 1.71 V–1.95 V	T = 25 °C	–	2.2	4.2	μA
	T = 125 °C		–	16.2	28	μA	
	Comparator = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF I ² C Wake = OFF POR = ON SIO Pins in single ended input, unregulated output mode	V _{DD} = V _{DDIO} = 2.7 V–3.6 V	T = 25 °C	–	2.2	2.7	μA
	I ² C Wake = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF Comparator = OFF POR = ON SIO Pins in single ended input, unregulated output mode	V _{DD} = V _{DDIO} = 2.7 V–3.6 V	T = 25 °C	–	2.2	2.8	μA

Notes

 26. If V_{cc}d and V_{cca} are externally regulated, the voltage difference between V_{cc}d and V_{cca} must be less than 50 mV.

27. Sleep timer generates periodic interrupts to wake up the CPU. This specification applies only to those times that the CPU is off.

Figure 11-20. Opamp Operating Current vs Vdda and Power Mode

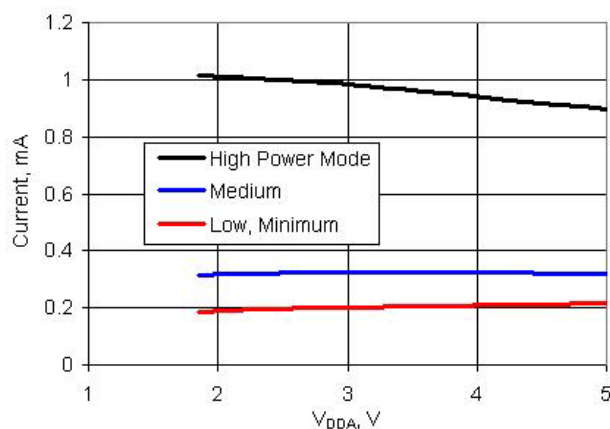
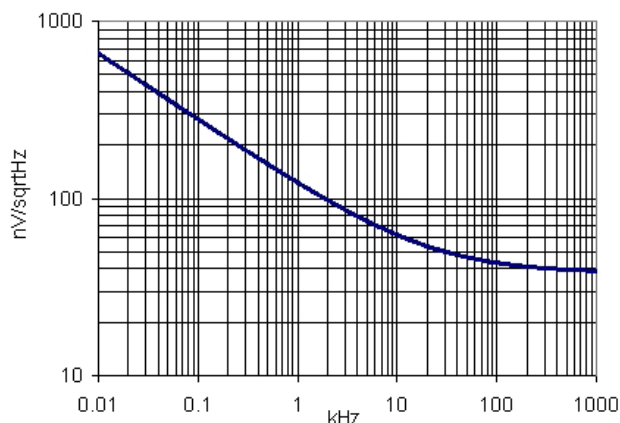


Table 11-16. Opamp AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
GBW	Gain-bandwidth product	Power mode = minimum, 15 pF load	1	—	—	MHz
		Power mode = low, 15 pF load	2	—	—	MHz
		Power mode = medium, 200 pF load	1	—	—	MHz
		Power mode = high, 200 pF load	2.5	—	—	MHz
SR	Slew rate, 20% - 80%	Power mode = low, 15 pF load	1.1	—	—	V/μs
		Power mode = medium, 200 pF load	0.9	—	—	V/μs
		Power mode = high, 200 pF load	3	—	—	V/μs
e _n	Input noise density	Power mode = high, Vdda = 5 V, at 100 kHz	—	45	—	nV/sqrtHz

Figure 11-21. Opamp Noise vs Frequency, Power Mode = High, Vdda = 5 V



11.5.2 Delta-Sigma ADC

Unless otherwise specified, operating conditions are:

- Operation in continuous sample mode
- fclk = 3.072 MHz for resolution = 16 to 20 bits; fclk = 6.144 MHz for resolution = 8 to 15 bits
- Reference = 1.024 V internal reference bypassed on P3.2 or P0.3
- Unless otherwise specified, all charts and graphs show typical values

Table 11-17. 20-bit Delta-sigma ADC DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Resolution		8	–	20	bits
	Number of channels, single ended		–	–	No. of GPIO	–
	Number of channels, differential	Differential pair is formed using a pair of GPIOs.	–	–	No. of GPIO/2	–
	Monotonic	Yes	–	–	–	–
Ge	Gain error	Buffered, buffer gain = 1, Range = ± 1.024 V, 16-bit mode, 25 °C	–	–	± 0.2	%
Gd	Gain drift	Buffered, buffer gain = 1, Range = ± 1.024 V, 16-bit mode	–	–	50	ppm/°C
Vos	Input offset voltage	Buffered, 16-bit mode, full voltage range	–	–	± 0.2	mV
		Buffered, 16-bit mode, $V_{DDA} = 1.8 \text{ V} \pm 5\%$	–	–	± 0.1	mV
TCVos	Temperature coefficient, input offset voltage	Buffer gain = 1, 16-bit, Range = ± 1.024 V	–	–	1	$\mu\text{V}/^\circ\text{C}$
	Input voltage range, single ended ^[36]		V_{SSA}	–	V_{DDA}	V
	Input voltage range, differential unbuffered ^[36]		V_{SSA}	–	V_{DDA}	V
	Input voltage range, differential, buffered ^[36]		V_{SSA}	–	$V_{DDA} - 1$	V
PSRRb	Power supply rejection ratio, buffered ^[36]	Buffer gain = 1, 16-bit, Range = ± 1.024 V	90	–	–	dB
CMRRb	Common mode rejection ratio, buffered ^[36]	Buffer gain = 1, 16 bit, Range = ± 1.024 V	85	–	–	dB
INL20	Integral non linearity ^[36]	Range = ± 1.024 V, unbuffered	–	–	± 32	LSB
DNL20	Differential non linearity ^[36]	Range = ± 1.024 V, unbuffered	–	–	± 1	LSB
INL16	Integral non linearity ^[36]	Range = ± 1.024 V, unbuffered; $2.7 \text{ V} \leq V_{DDA} \leq 5.5 \text{ V}$ range	–	–	± 2	LSB
		$1.71 \text{ V} \leq V_{DDA} < 2.7 \text{ V}$ range	–2.1	–	+2.7	LSB
DNL16	Differential non linearity ^[36]	Range = ± 1.024 V, unbuffered; $2.7 \text{ V} \leq V_{DDA} \leq 5.5 \text{ V}$ range	–	–	± 1	LSB
		$1.71 \text{ V} \leq V_{DDA} < 2.7 \text{ V}$ range	–1	–	+1.1	LSB
INL12	Integral non linearity ^[36]	Range = ± 1.024 V, unbuffered	–	–	± 1	LSB
DNL12	Differential non linearity ^[36]	Range = ± 1.024 V, unbuffered	–	–	± 1	LSB
INL8	Integral non linearity ^[36]	Range = ± 1.024 V, unbuffered	–	–	± 1	LSB
DNL8	Differential non linearity ^[36]	Range = ± 1.024 V, unbuffered	–	–	± 1	LSB

Note

³⁶. Based on device characterization (not production tested).

Table 11-23. Delta-sigma ADC RMS Noise in Counts vs. Input Range and Sample Rate, 20-bit, External Reference, Differential

Sample rate, sps	Input Voltage Range				
	±VREF	±VREF / 2	±VREF / 4	±VREF / 8	±VREF / 16
8	0.70	0.84	1.02	1.40	2.65
11.3	0.69	0.86	0.96	1.40	2.69
22.5	0.73	0.82	1.25	1.77	2.67
45	0.76	0.94	1.02	1.76	2.75
61	0.75	1.01	1.13	1.65	2.98
170	0.75	0.98	INVALID OPERATING REGION		
187	0.73				

Figure 11-28. Delta-sigma ADC DNL vs Output Code, 16-bit, 48 ksps, 25 °C $V_{DDA} = 3.3$ V

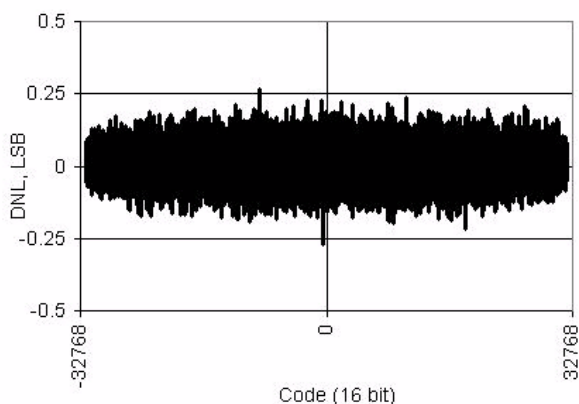


Figure 11-29. Delta-sigma ADC INL vs Output Code, 16-bit, 48 ksps, 25 °C $V_{DDA} = 3.3$ V

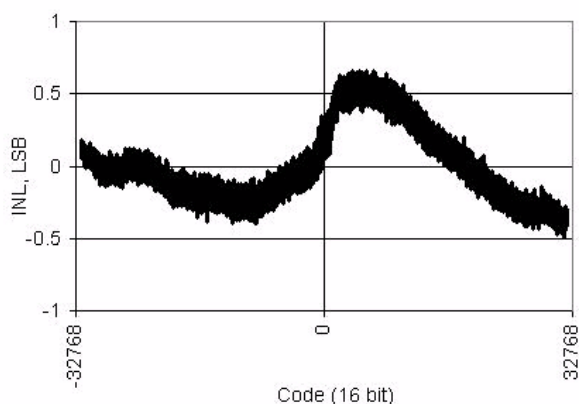


Table 11-31. VDAC (Voltage Digital-to-Analog Converter) AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Fdac	Update rate ^[30]	1 V mode	-	-	1	Msp/s
	Update rate ^[30]	4 V mode			250	Ksp/s
TsettleP	Settling time to 0.1%, step 25% to 75%	1 V scale, Cload = 15 pF	-	0.45	1	μs
		4 V scale, Cload = 15 pF	-	0.8	3.2	μs
TsettleN	Settling time to 0.1%, step 75% to 25%	1 V scale, Cload = 15 pF	-	0.45	1	μs
		4 V scale, Cload = 15 pF	-	0.7	3	μs
	Voltage noise	Range = 1 V, High speed mode, Vdda = 5 V, 10 kHz	-	750	-	nV/sqrtHz

Figure 11-54. VDAC Step Response, Codes 0x40 - 0xC0, 1 V Mode, High speed mode, Vdda = 5 V

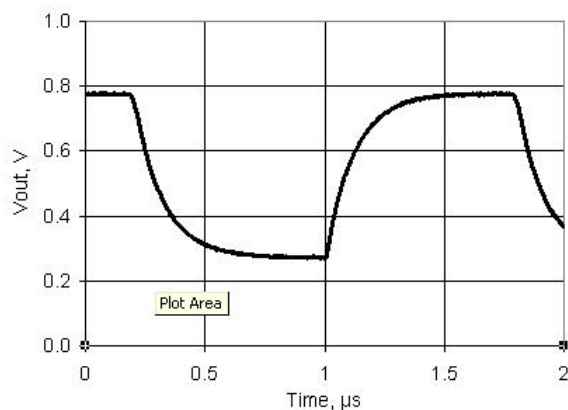
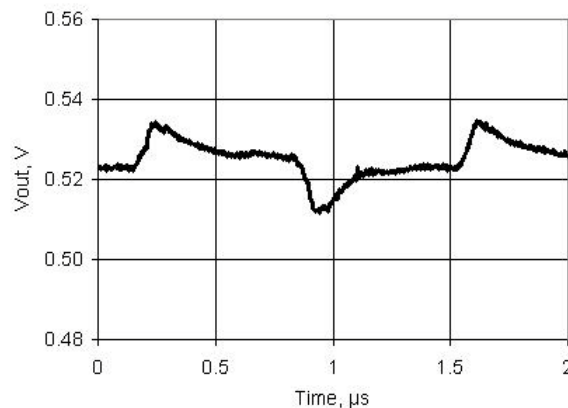


Figure 11-55. VDAC Glitch Response, Codes 0x7F - 0x80, 1 V Mode, High speed mode, Vdda = 5 V



11.5.9 Transimpedance Amplifier

The TIA is created using a SC/CT Analog Block, see the TIA component data sheet in PSoC Creator for full AC/DC specifications, and APIs and example code.

Table 11-34. Transimpedance Amplifier (TIA) DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Vioff	Input offset voltage		-	-	10	mV
Rconv	Conversion resistance ^[46]					
	R = 20K	40 pF load	-25	-	+35	%
	R = 30K	40 pF load	-25	-	+35	%
	R = 40K	40 pF load	-25	-	+35	%
	R = 80K	40 pF load	-25	-	+35	%
	R = 120K	40 pF load	-25	-	+35	%
	R = 250K	40 pF load	-25	-	+35	%
	R = 500K	40 pF load	-25	-	+35	%
	R = 1M	40 pF load	-25	-	+35	%
	Quiescent current		—	1.1	2	mA

Table 11-35. Transimpedance Amplifier (TIA) AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
BW	Input bandwidth (–3 dB)	R = 20K; –40 pF load	1000	—	—	kHz
		R = 120K; –40 pF load	220	—	—	kHz
		R = 1M; –40 pF load	25	—	—	kHz

Note

46. Conversion resistance values are not calibrated. Calibrated values and details about calibration are provided in PSoC Creator component data sheets. External precision resistors can also be used.

11.6.3 Pulse Width Modulation

Table 11-45. PWM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Block current consumption	16-bit PWM, at listed input clock frequency	–	–	–	μA
	3 MHz		–	15	–	μA
	12 MHz		–	60	–	μA
	50 MHz		–	260	–	μA
	67 MHz		–	350	–	μA

Table 11-46. Pulse Width Modulation (PWM) AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Operating frequency	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	DC	–	67 ^[49]	MHz
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	DC	–	50	MHz
	Pulse width	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	15	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	21	–	–	ns
	Pulse width (external)	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	30	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	42	–	–	ns
	Kill pulse width	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	15	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	21	–	–	ns
	Kill pulse width (external)	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	30	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	42	–	–	ns
	Enable pulse width	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	15	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	21	–	–	ns
	Enable pulse width (external)	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	30	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	42	–	–	ns
	Reset pulse width	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	15	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	21	–	–	ns
	Reset pulse width (external)	$-40^{\circ}\text{C} \leq T_a \leq 85^{\circ}\text{C}$ and $T_j \leq 100^{\circ}\text{C}$	30	–	–	ns
		$-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$	42	–	–	ns

Note

 49. Applicable at -40°C to 85°C ; 50 MHz at -40°C to 125°C .

11.7.2 EEPROM

Table 11-57. EEPROM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage		1.71	-	5.5	V

Table 11-58. EEPROM AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T _{WRITE}	Single row erase/write cycle time		–	2	20	ms
	EEPROM data retention time, retention period measured from last erase cycle	Average ambient temp, T _A ≤ 25 °C, 1M erase/program cycles	20	–	–	years
		Average ambient temp, T _A ≤ 55 °C, 100 K erase/program cycles	20	–	–	
		Average ambient temp, T _A ≤ 85 °C, 10 K erase/program cycles	10	–	–	

11.7.3 Nonvolatile Latches (NVL)

Table 11-59. NVL DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage	V _{ddd} pin	1.71	-	5.5	V

Table 11-60. NVL AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	NVL endurance	Programmed at 25°C	1K	-	-	program/erase cycles
		Programmed at 0-70°C	100	-	-	program/erase cycles
	NVL data retention time	Programmed at 55°C	20	-	-	years
		Programmed at 0-70°C	10	-	-	years

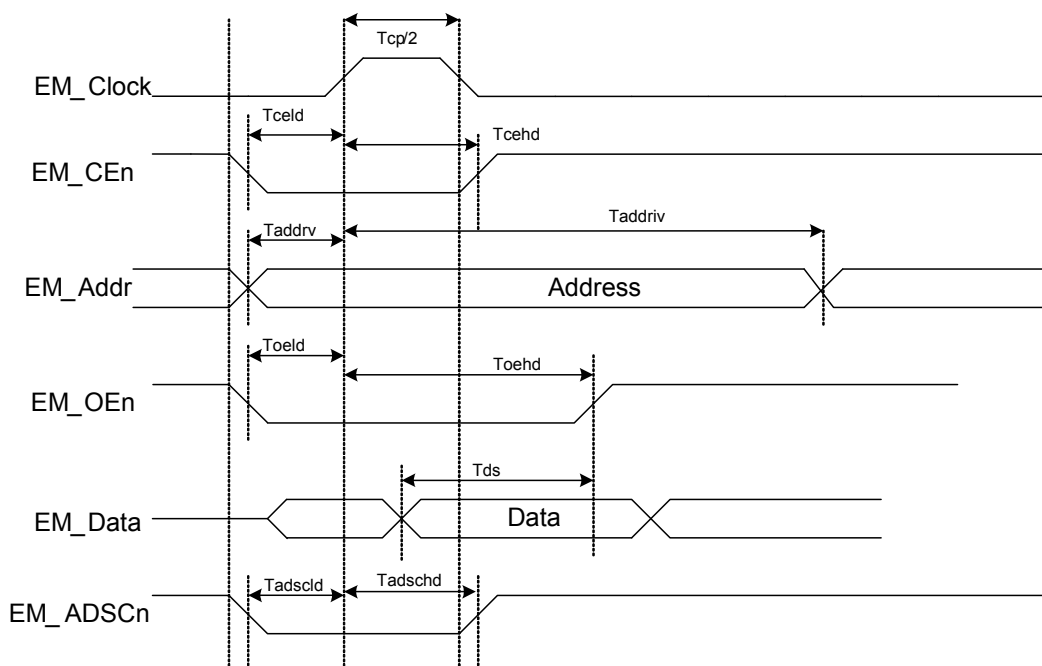
11.7.4 SRAM

Table 11-61. SRAM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V _{sram}	SRAM retention voltage		1.2	-	-	V

Table 11-62. SRAM AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F _{sram}	SRAM operating frequency	-40°C ≤ T _a ≤ 85°C and T _j ≤ 100°C	DC	-	67	MHz
		-40°C ≤ T _a ≤ 125°C and T _j ≤ 150°C	DC	-	50	MHz

Figure 11-63. Synchronous Read Cycle Timing

Table 11-65. Synchronous Read Cycle Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T	EMIF clock period ^[57]	V _{dda} ≥ 3.3 V	30.3	–	–	ns
Tcp/2	EM_Clock pulse high		T/2	–	–	ns
Tceld	EM_CEn low to EM_Clock high		5	–	–	ns
Tcehd	EM_Clock high to EM_CEn high		T/2 – 5	–	–	ns
Taddrv	EM_Addr valid to EM_Clock high		5	–	–	ns
Taddriv	EM_Clock high to EM_Addr invalid		T/2 – 5	–	–	ns
Toeld	EM_OEn low to EM_Clock high		5	–	–	ns
Toehd	EM_Clock high to EM_OEn high		T	–	–	ns
Tds	Data valid before EM_OEn high		T + 15	–	–	ns
Tadscl	EM_ADSCn low to EM_Clock high		5	–	–	ns
Tadschd	EM_Clock high to EM_ADSCn high		T/2 – 5	–	–	ns

Note

57. Limited by GPIO output frequency, see .

Figure 11-64. Synchronous Write Cycle Timing

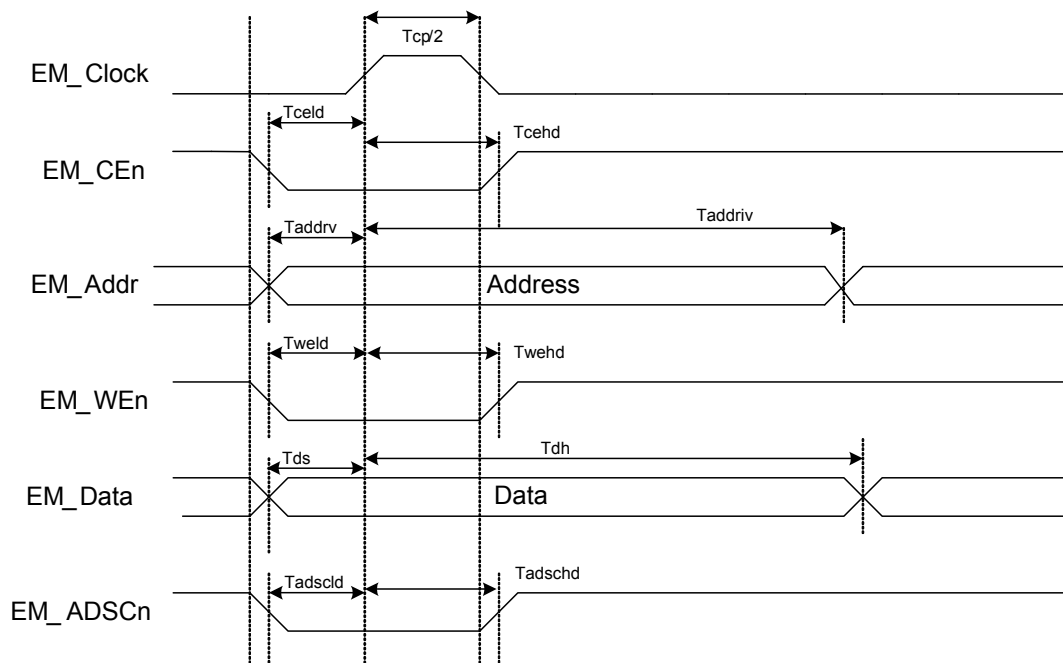


Table 11-66. Synchronous Write Cycle Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T	EMIF clock Period ^[58]	V _{dda} ≥ 3.3 V	30.3	–	–	ns
Tcp/2	EM_Clock pulse high		T/2	–	–	ns
Tceld	EM_CEn low to EM_Clock high		5	–	–	ns
Tcehd	EM_Clock high to EM_CEn high		T/2 – 5	–	–	ns
Taddrv	EM_Addr valid to EM_Clock high		5	–	–	ns
Taddrv	EM_Clock high to EM_Addr invalid		T/2 – 5	–	–	ns
Tweld	EM_WEn low to EM_Clock high		5	–	–	ns
Twehd	EM_Clock high to EM_WEn high		T/2 – 5	–	–	ns
Tds	Data valid before EM_Clock high		5	–	–	ns
Tdh	Data invalid after EM_Clock high		T	–	–	ns
Tadscl	EM_ADSCn low to EM_Clock high		5	–	–	ns
Tadschd	EM_Clock high to EM_ADSCn high		T/2 – 5	–	–	ns

Note

58. Limited by GPIO output frequency, see .

11.9 Clocking

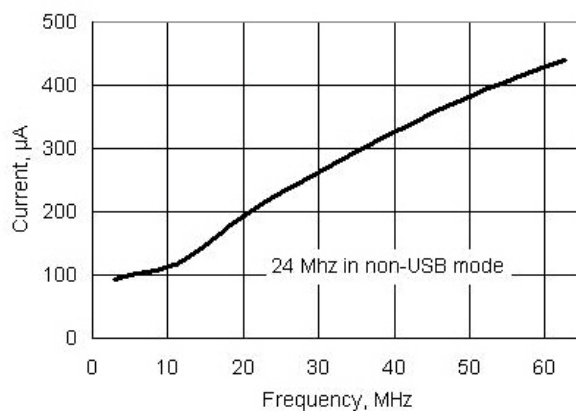
Specifications are valid for $-40^{\circ}\text{C} \leq T_a \leq 125^{\circ}\text{C}$ and $T_j \leq 150^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.9.1 Internal Main Oscillator

Table 11-75. IMO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Supply current					
	62.6 MHz		–	–	600	μA
	48 MHz		–	–	500	μA
	24 MHz – USB mode	With oscillator locking to USB bus	–	–	500	μA
	24 MHz – non USB mode		–	–	300	μA
	12 MHz		–	–	200	μA
	6 MHz		–	–	180	μA
	3 MHz		–	–	150	μA

Figure 11-67. IMO Current vs. Frequency



13. Packaging

Table 13-1. Package Characteristics

Parameter	Description	Conditions	Min	Typ	Max	Units
T _A	Operating ambient temperature		-40	25.00	125	°C
T _J	Operating junction temperature		-40	—	150	°C
T _{JA}	Package θ _{JA} (48-pin SSOP)		—	49	—	°C/W
T _{JA}	Package θ _{JA} (100-pin TQFP)		—	34	—	°C/W
T _{JC}	Package θ _{JC} (48-pin SSOP)		—	24	—	°C/W
T _{JC}	Package θ _{JC} (100-pin TQFP)		—	10	—	°C/W

Table 13-2. Solder Reflow Peak Temperature

Package	Maximum Peak Temperature	Maximum Time at Peak Temperature
48-pin SSOP	260 °C	30 seconds
100-pin TQFP	260 °C	30 seconds

Table 13-3. Package Moisture Sensitivity Level (MSL), IPC/JEDEC J-STD-2

Package	MSL
48-pin SSOP	MSL 3
100-pin TQFP	MSL 3

Figure 13-1. 48-pin SSOP (300 Mils) O483 Package Outline, 51-85061

